

## Graphene on Polycrystalline Ni Thin Film: Mapping Conductivity by Conducting Atomic Force Microscopy

Yunyi Fu<sup>1</sup>, Huabo Zhao<sup>1</sup>, Qingin Wei<sup>1</sup>, Zhijun Wei<sup>1</sup>, Zhaohui Zhang<sup>2</sup>, Zujin Shi<sup>3</sup>,  
Xing Zhu<sup>2</sup>, Ru Huang<sup>1</sup> and Xing Zhang<sup>1</sup>

<sup>1</sup>Department of Microelectronics, Peking University, Beijing 100871, People's Republic of China

<sup>2</sup>School of Physics, Peking University, Beijing 100871, China,

<sup>3</sup>College of Chemistry and Molecular Engineering, Peking University, Beijing 100871, People's Republic of China  
yyfu@pku.edu.cn

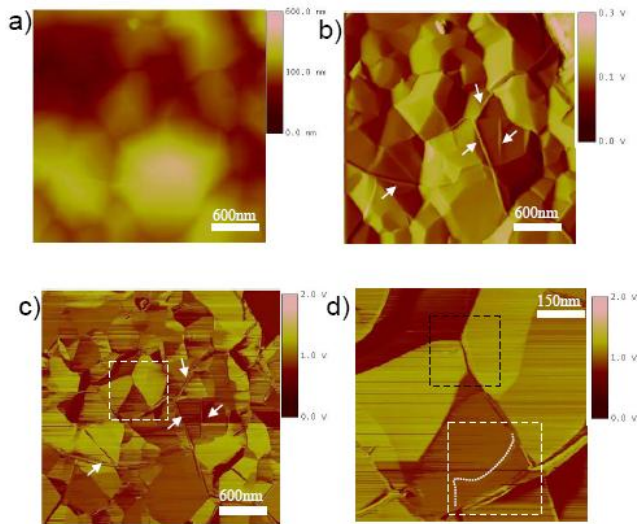
Conducting Atomic Force microscopy (C-AFM) has been used to map the local conductivity of mono- or few-layer graphene grown on polycrystalline Ni thin films on SiO<sub>2</sub>/Si substrate. It has been revealed that the local conductivity of graphene depend strongly on the crystal face of underlying Ni crystal. There exists a transition zone between the two adjacent surfaces, where the graphene has unique conductivity properties. Using C-AFM, combining with analysis of the graphene/Ni moiré pattern, we also characterize the graphene morphologies underneath the top graphene sheets, which provide clear evidence for CVD growth of graphene on Ni occurring by carbon segregation. Our findings are important for understanding both the physical properties of graphene sheets and their growth mechanism.

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## References

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## Figures



### Figure caption

*Local conductance maps on the three dimensional Ni crystals:*

*(a) Larger scale of topography of the graphene on Ni crystals;*

*(b) Deflection image of the topography;*

*(c) The conductance map composed of many flat patches with various contrasts corresponding to different facets of the Ni crystals;*

*(d) The magnified region indicated by the white box in Figure 2c*